

UNISONIC TECHNOLOGIES CO., LTD

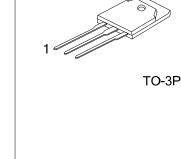
26N50 **Preliminary Power MOSFET**

26A, 500V N-CHANNEL **POWER MOSFET**

DESCRIPTION

The UTC 26N50 is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology allows a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

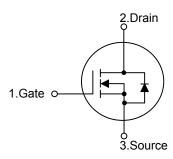
The UTC 26N50 is generally applied in high efficiency switch mode power supplies, active power factor correction and electronic lamp ballasts based on half bridge topology.



FEATURES

- * $R_{DS(ON)}$ =0.24 Ω @ V_{GS} =10V
- * High Switching Speed
- * 100% Avalanche Tested

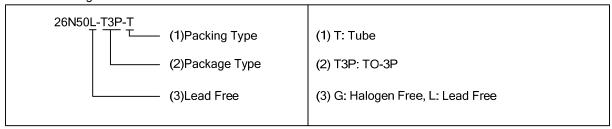
SYMBOL



ORDERING INFORMATION

Ordering Number		Dooksons	Pin Assignment			Darling	
Lead Free	Halogen Free	Package	1	2	3	Packing	
26N50L-T3P-T	26N50G-T3P-T	TO-3P	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



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■ **ABSOLUTE MAXIMUM RATINGS** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	500	V
Gate-Source Voltage		V_{GSS}	±30	V
Dunin Commant	Continuous (T _C =25°C)	I _D	24(Note 2)	Α
Drain Current	Pulsed (Note 3)	I _{DM}	96 (Note 2)	Α
Avalanche Current (Note 3)		I _{AR}	26	Α
A	Single Pulsed (Note 4)	E _{AS}	1100	mJ
Avalanche Energy	Repetitive (Note 5)	E _{AR}	29	mJ
Peak Diode Recovery dv/dt (Note 5)		dv/dt	15	V/ns
Power Dissipation		Б	290	W
Derate above 25°C		P _D	2.33	W/°C
Junction Temperature		TJ	+150	°C
Storage Temperature		T _{STG}	-55~+150	°C

Note: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Drain current limited by maximum junction temperature
- 3. Repetitive Rating: Pulse width limited by maximum junction temperature
- 4. L =3.4mH, I_{AS} = 26A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 5. $I_{SD} \le 26A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	40	°C/W	
Junction to Case	θ_{JC}	0.43	°C/W	

■ ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	LINIT		
PARAIVIETER		STIVIBUL	TEST CONDITIONS	IVIIIN	ITP	IVIAA	UNIT		
OFF CHARACTERISTICS									
Drain-Source Breakdown Voltage	е	BV_{DSS}	$I_D=250\mu A, V_{GS}=0V$	500			V		
Drain-Source Leakage Current		I_{DSS}	V _{DS} =500V, V _{GS} =0V			50	μΑ		
Cata Sauraa Laakaga Current	Forward	1000	V_{GS} =+30V, V_{DS} =0V			+100	nA		
Gate- Source Leakage Current	Reverse		V_{GS} =-30V, V_{DS} =0V			-100	nA		
ON CHARACTERISTICS									
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$	2.0		4.0	V		
Static Drain-Source On-State Re	sistance		V _{GS} =10V, I _D =13A		0.15	0.24	Ω		
DYNAMIC PARAMETERS									
Input Capacitance		C_{ISS}			3500	4500	pF		
Output Capacitance		Coss	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		520	670	pF		
Reverse Transfer Capacitance		C_{RSS}			55	70	pF		

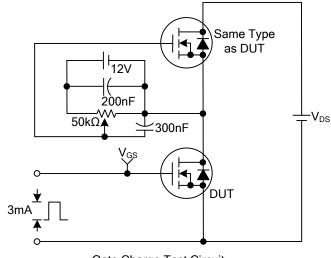
■ ELECTRICAL CHARACTERISTICS(Cont.)

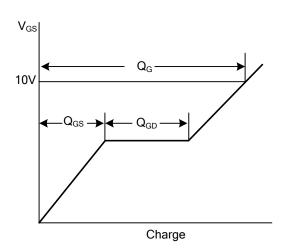
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
SWITCHING PARAMETERS								
Total Gate Charge	Q_{G}	\\ 40\\\\\ 400\\\\\\\\\\\\\\\\\\\\\\\\\		90	120	nC		
Gate to Source Charge	Q_GS	V _{GS} =10V, V _{DS} =400V, I _D =26A		23		nC		
Gate to Drain Charge	Q_GD	(Note 1, 2)		52		nC		
Turn-ON Delay Time	t _{D(ON)}			80	170	ns		
Rise Time	t _R	V_{DD} =250V, I_{D} =26A, R_{G} =25 Ω		250	500	ns		
Turn-OFF Delay Time	t _{D(OFF)}	(Note 1, 2)		200	400	ns		
Fall-Time	t_{F}			155	320	ns		
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Current	Is				24	Α		
Maximum Body-Diode Pulsed Current	I _{SM}				96	Α		
Drain-Source Diode Forward Voltage	V _{SD}	I _S =26A, V _{GS} =0V			1.4	V		
Body Diode Reverse Recovery Time	t _{rr}	I _S =26A, V _{GS} =0V,		250		ns		
Body Diode Reverse Recovery Charge	Q_{RR}	dI _F /dt=100A/μs (Note 1)		1.1		μC		

Note: 1. Pulse Test: Pulse width ≤ 300μs, Duty cycle ≤ 2%

2. Essentially independent of operating temperature

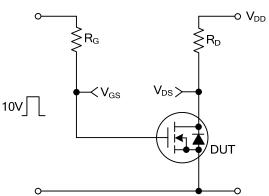
■ TEST CIRCUITS AND WAVEFORMS



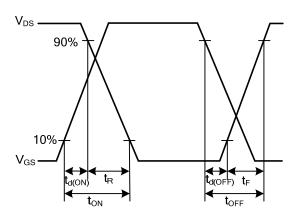


Gate Charge Test Circuit

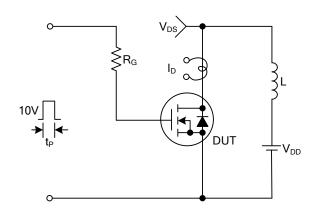
Gate Charge Waveforms



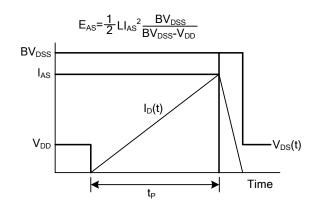




Resistive Switching Waveforms

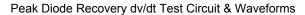


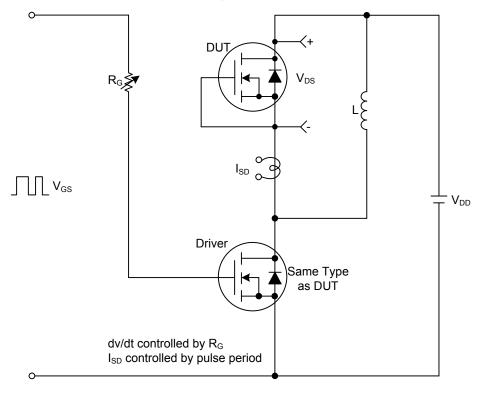
Unclamped Inductive Switching Test Circuit

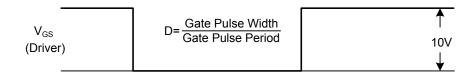


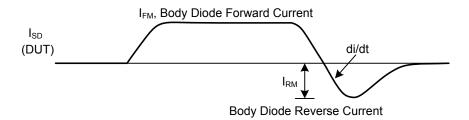
Unclamped Inductive Switching Waveforms

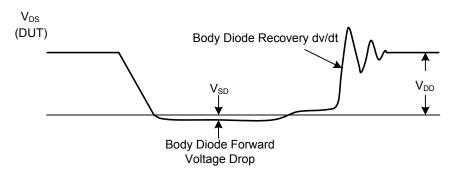
■ TEST CIRCUITS AND WAVEFORMS(Cont.)











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